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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10088591	07/29/2002	324	736	2862	NGUYEN, TUNG

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2829

**CONTINUING DATA VERIFIED:

This application is a 371 of PCT/DE00/03231 09/18/2000

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** FOREIGN APPLICATIONS VERIFIED:

GERMANY 19945178.8 09/21/1999

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed	<input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO	
35 USC 119 conditions met	<input type="checkbox"/> yes <input type="checkbox"/> no		2134-022
Verified and Acknowledged Examiner's initials			
TITLE : Mesuring probe for measuring high frequencies and a method for producing the same			
U.S. DEPT. OF COMM./PAT. & TM-PTO-438L (Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claims w/ O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drawn	Fig.s Drawn
TERMINAL DISCLAIMER		Primary Examiner	
		Application Examiner	
PREPARED FOR ISSUE			
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